

Search Notes

Application/Control No.

10/779,779

Examiner

W. Patty Chen

Applicant(s)/Patent under
Reexamination

NIIYA, HIROTAKA

Art Unit

2871

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
reviewed previously cited references	12/29/2006	WPC
citations search of tagged reference	12/29/2006	WPC